TOSHIBA CMOS Linear Integrated Circuit Silicon Monolithic

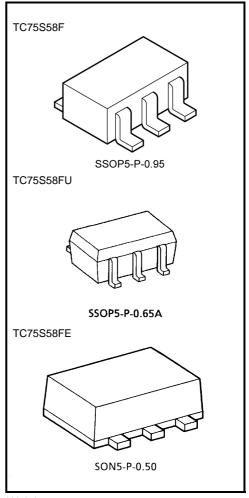
TC75S58F,TC75S58FU,TC75S58FE

Single Comparator

The TC75S58F/TC75S58FU/TC75S58FE is a CMOS general-purpose single comparator. The device can operate off a single power supply and draws a lower supply current than a conventional bipolar general-purpose comparator. This device's open-drain output stage can be wire-ORed with those of other open-drain output circuits.

Features

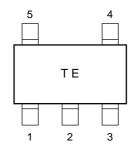
- Low-current power supply : $IDD = 10 \mu A \text{ (typ.)}$
- · Single power supply operation
- Wide common mode input voltage range: VSS~VDD 0.9 V
- Open drain output circuit
- Low input bias current
- · Small package



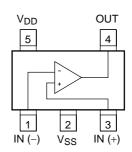
Weight

SSOP5-P-0.95 : 0.014 g (typ.) SSOP5-P-0.65A : 0.006 g (typ.) SON5-P-0.50 : 0.003 g (typ.)

Marking (top view)



Pin Connection (top view)





Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Supply voltage		V _{DD} , V _{SS}	±3.5 or 7	V	
Differential input voltage		DV _{IN}	±7	V	
Input voltage		V _{IN}	$V_{SS} \sim V_{DD}$	V	
Output current	current		±35	mA	
Power dissipation	TC75S58F/FU	P _D	200	mW	
	TC75S58FE		100		
Operating tempera	ture	T _{opr} -40~85 °0		°C	
Storage temperature		T _{stg}	-55~125	°C	

Note: This device's CMOS structure makes it prone to latch-up. To prevent latch-up, please take the following precautions:

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- Ensure that no I/O pin's voltage level ever exceeds V_{DD} or drops below V_{SS}.
 In addition, check the power-on timing.
- Do not subject the device to excessive noise.



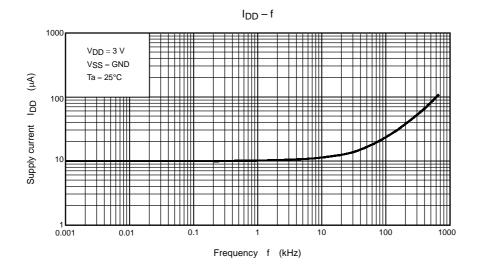
Electrical Characteristics ($V_{DD} = 5 V$, $V_{SS} = GND$, Ta = 25°C)

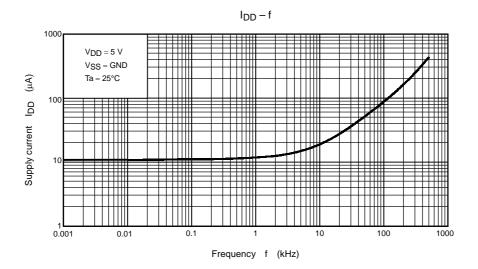
Characteristics	Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Input offset voltage	V _{IO}	_	_	_	±1	±7	mV
Input offset current	I _{IO}	_	_	_	1	_	pА
Input bias current	lı	_	_	_	1	_	pА
Common mode input voltage	CMVIN	_	_	0	_	4.1	V
Supply current	I _{DD} (Note)	_	_	_	11	22	μΑ
Voltage gain	G _V	_	_	_	94	_	dB
Sink current	I _{sink}	_	V _{OL} = 0.5 V	13	25	_	mA
Output leak current	I _{LEAK}	_	V _O = 5 V	_	5	_	nA
Output voltage	V _{OL}	_	I _{sink} = 5.0 mA	_	0.1	0.3	V
Operating supply voltage	V _{DD}	_	_	1.8	_	7.0	V
Propagation delay time (turn on)	t _{PLH} (1)	_	Over drive = 100 mV	_	800	_	- ns
Propagation delay time (turn on)	t _{PLH} (2)	_	TTL step input	_	620	_	
Propagation delay time (turn off)	t _{PHL} (1)	_	Over drive = 100 mV	_	230	_	ns
	t _{PHL} (2)	_	TTL step input	_	350	_	
Response time	t _{TLH}	_	Over drive = 100 mV	_	190	_	- ns
	t _{THL}	_	Over drive = 100 mV	_	6	_	

Electrical Characteristics ($V_{DD} = 3 V$, $V_{SS} = GND$, Ta = 25°C)

Characteristics	Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Input offset voltage	V _{IO}	_	_	_	±1	±7	mV
Input offset current	I _{IO}	_	_	_	1	_	pА
Input bias current	l _l	_	_	_	1	_	pА
Common mode input voltage	CMV _{IN}	_	_	0	_	2.1	V
Supply current	I _{DD} (Note)	_	_	_	10	20	μА
Sink current	I _{sink}	_	V _{OL} = 0.5 V	6	18	_	mA
Output leak current	I _{LEAK}	_	V _O = 3 V	_	5	_	nA
Output voltage	V _{OL}	_	I _{sink} = 5.0 mA	_	0.15	0.35	V
Propagation delay time (turn on)	t _{PLH}	_	Over drive = 100 mV	_	590	_	ns
Propagation delay time (turn off)	t _{PHL}	_	Over drive = 100 mV	_	230	_	ns
Response time	t _{TLH}	_	Over drive = 100 mV	_	170	_	ns
	t _{THL}	_	Over drive = 100 mV	_	5	_	115

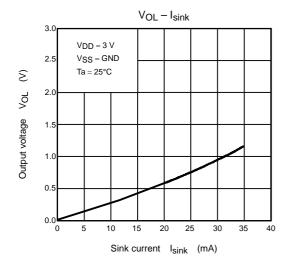
Note: This device's current consumption increases as its operating frequency increases. Note that the power dissipation should not exceed the allowable power dissipation.

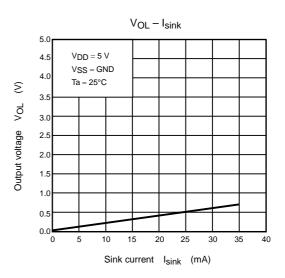


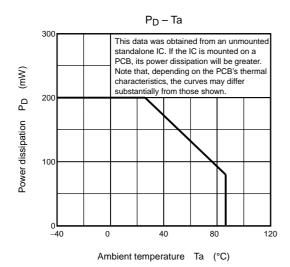


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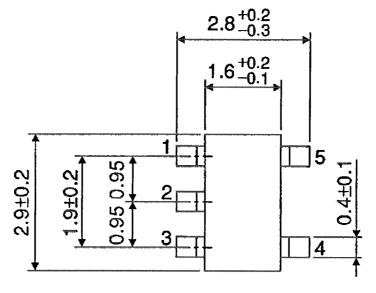


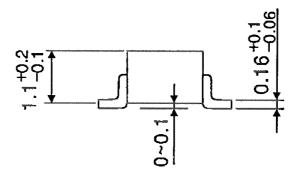
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TC75S58F/FU/FE

Package Dimensions

SSOP5-P-0.95 Unit: mm





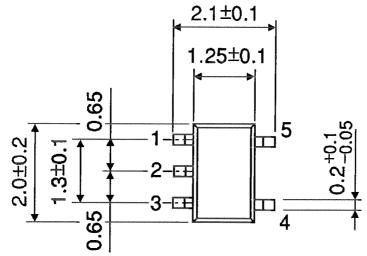
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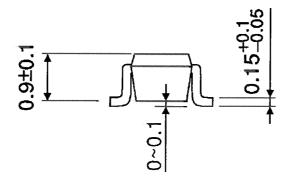
Weight: 0.014 g (typ.)

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Package Dimensions

SSOP5-P-0.65A Unit: mm





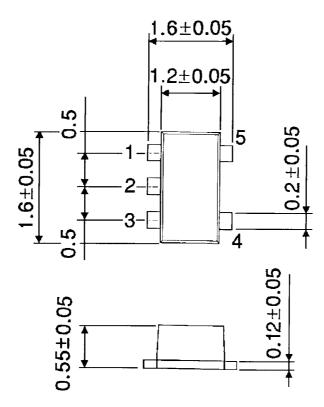
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Weight: 0.006 g (typ.)



Package Dimensions

SON5-P-0.50 Unit: mm



Weight: 0.003 g (typ.)

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